October 2009

UniFET™

SEMICONDUCTOR®

FDP16N50U / FDPF16N50UT N-Channel MOSFET, FRFET 500V, 15A, 0.48 Ω

Features

- + $R_{DS(on)} = 0.37\Omega$ (Typ.) @ $V_{GS} = 10V$, $I_D = 7.5A$
- Low gate charge (Typ. 32nC)
- Low C_{rss} (Typ. 20pF)
- · Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- RoHS compliant



TO-220F

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switching mode power supplies and active power factor correction.

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TO-220

Symbol		FDP16N50U	FDPF16N50UT	Units		
V _{DSS}	Drain to Source Voltage	Drain to Source Voltage			500	
V _{GSS}	Gate to Source Voltage			±30		V
1	Drain Current	-Continuous (T _C = 25°C)		15	15*	A
I _D		-Continuous ($T_C = 100^{\circ}C$)		9	9*	
I _{DM}	Drain Current	- Pulsed	(Note 1)	60	60*	Α
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		610		mJ	
I _{AR}	Avalanche Current		(Note 1)	15		Α
E _{AR}	Repetitive Avalanche Energy		(Note 1)	20		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3		(Note 3)	20		V/ns
P _D	Power Dissipation	$(T_{\rm C} = 25^{\rm o}{\rm C})$		200	38.5	W
		- Derate above 25°C		1.59	0.3	W/ºC
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +150		°C
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300		°C
Drain current li	mited by maximum junction tempe	rature				

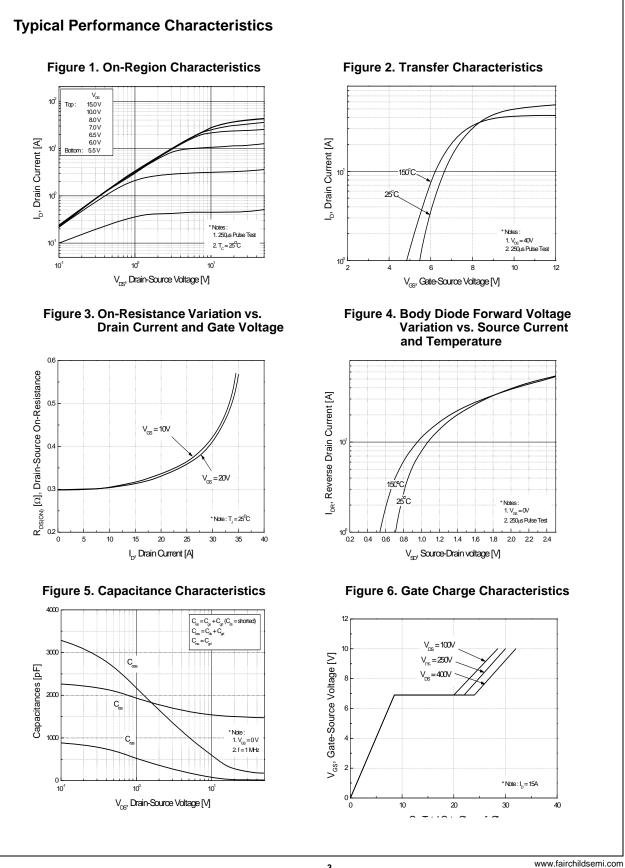
Thermal Characteristics

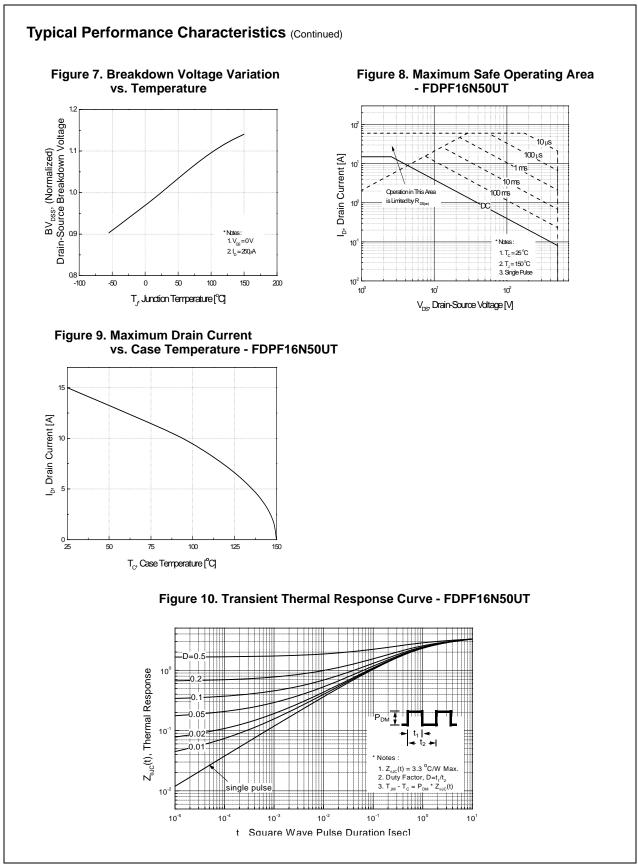
Symbol	Parameter	FDP16N50U	FDPF16N50UT	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.63	3.3	
$R_{\theta CS}$	Thermal Resistance, Junction to Ambient	0.5	-	°C/W
R_{\thetaJA}	Thermal Resistance, Junction to Ambient	62.5	62.5	

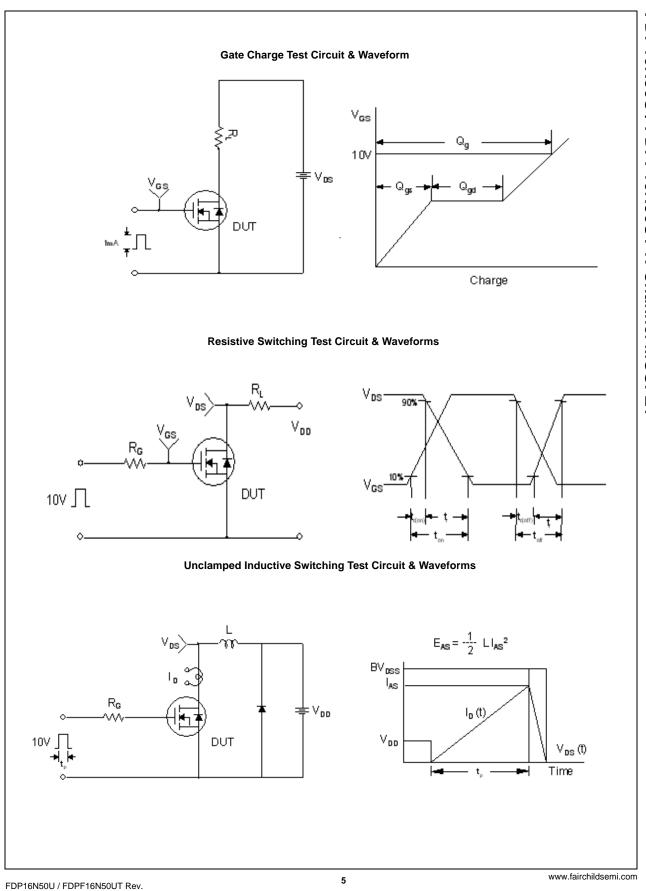
©2009 Fairchild Semiconductor Corporation FDP16N50U / FDPF16N50UT Rev. A1



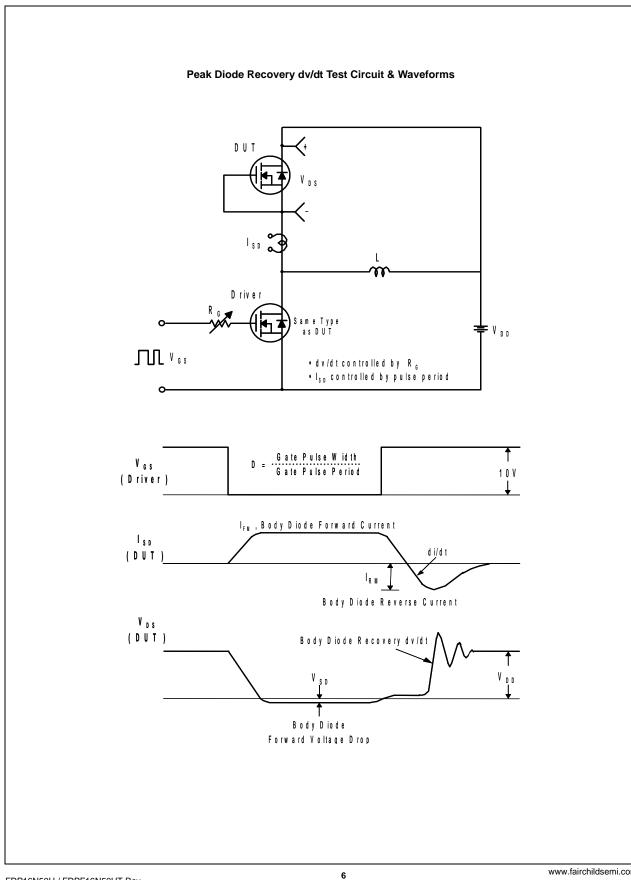
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Electrical Characteristics Symbol Parameter Test Conditions Min. Typ. Max. Ur Off Characteristics BVpSs Drain to Source Breakdown Voltage Ip = 250µA, VGS = 0V, TJ = 25°C 500 - - V/ ABVpSs Breakdown Voltage Temperature Ip = 250µA, Referenced to 25°C - 0.5 - V/ ABVpSs Zero Gate Voltage Drain Current VDS = 500V, VGS = 0V - - 250 µ VpS = dato V, TG = 125°C - - 250 µ VpS = dato V, TG = 125°C - - 250 µ VpS = dato V, TG = 125°C - - 250 µ VpS = dato V, TG = 125°C - - 100 n On Characteristics On Characteristics - 0.37 0.48 6 VpS(n) Gate Threshold Voltage VpS = 400V, VpS = 400V, Vp = 7.5A - 0.37 0.48 6 Dynamic Characteristics C - 23 310 p - 23 310 p Qate to Drain Taillef Charage a			TO-220			-		50		
SymbolParameterTest ConditionsMin.Typ.Max.UrOff Characteristics \mathbb{B}^{V}_{DSS} Drain to Source Breakdown Voltage $I_0 = 250 \mu A, V_{GS} = 0V, T_J = 25^{\circ}C$ 500 $ \Lambda$ ABV_{DSS} Breakdown Voltage Temperature $I_0 = 250 \mu A, Referenced to 25^{\circ}C 0.5 V/V_{DS}ABV_{DSS}Zero Gate Voltage Drain CurrentV_{DS} = 500V, V_{CS} = 0V 250V/V_{DS}I_{0SS}Gate to Body Leakage CurrentV_{GS} = 430V, V_{DS} = 0V 250\muV_{OSS} = 0VSate Threshold VoltageV_{GS} = 130V, V_{DS} = 0V +100nOn CharacteristicsVasion Transcored Under ResistanceV_{GS} = 10V, I_D = 7.5A0.0.370.48\sigmaOutput CapacitanceV_{DS} = 25V, V_{CS} = 0V 14951945pC_{IBS}Input CapacitanceV_{DS} = 25V, V_{CS} = 0V 14951945pC_{IBS}Input CapacitanceV_{DS} = 400V, I_D = 15A 3.0 3.245nQ_{20}Total Gate Charge at 10VV_{DS} = 400V, I_D = 15A 3.0nnnQ_{20}Gate to Source Gate ChargeV_{DS} = 250L 140nnnnnnnnnnnnnn$				TO-220F	-		-			
Off Characteristics BV _{DSS} Drain to Source Breakdown Voltage Ip = 250µA, V _{GS} = 0V, T _j = 25°C 500 - N ABV _{DSS} Drain to Source Breakdown Voltage Temperature Ip = 250µA, Referenced to 25°C - 0.5 - V ABV_DSS Zero Gate Voltage Drain Current V _{DS} = 500V, V _{GS} = 0V - - 2.55 µµ Gate to Body Leakage Current V _{DS} = 500V, V _{GS} = 0V - - 2.50 N ON Characteristics Vgs = V_OS D = 250µA 3.0 - 5.0 N Vgs = V_OS D = 250µA 3.0 - 5.0 N VGS = V_OS C 1495 P VGS = V/OS = 0V 1 1495 P VGS = 104 N <th>Electrica</th> <th>al Chai</th> <th>racteristics</th> <th></th> <th></th> <th></th> <th></th> <th></th> <th></th> <th></th>	Electrica	al Chai	racteristics							
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$ \frac{\Delta BV_{DSS}}{\Delta T_{a}} = \frac{Breakdown Voltage Temperature}{Coefficient} l_{D} = 250\muA, Referenced to 25°C - 0.5 $	BV _{DSS}	Drain t	o Source Breakdown Vo	oltage	$I_{\rm D} = 250 \mu A, V_{\rm GS} = 0$	/, T _{.1} = 25°C	500	-	-	V
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		Coeffic	ient				-	0.5	-	v/ C
Non- VDS = 400V, I_C = 129°C - - 250 - IdgsS Gate to Body Leakage Current VGS = ±30V, VDS = 0V - - ±100 n On Characteristics VGS(th) Gate Threshold Voltage VGS = VDS, ID = 250µA 3.0 - 5.0 N RpSig(n) Static Drain to Source On Resistance VGS = 10V, ID = 7.5A - 0.37 0.48 6 grs Forward Transconductance VDS = 25V, VGS = 0V - 1495 1945 p Ciss Input Capacitance VDS = 25V, VGS = 0V - 1495 1945 p Qi(cot) Total Gate Charge at 10V VDS = 25V, VGS = 0V - 1495 1945 p Qi(cot) Total Gate Charge at 10V VDS = 25V, VGS = 0V - 144 - n Qi(cot) Total Gate Charge at 10V VDS = 400V, ID = 15A - 40 90 n Qi(cot) Turn-On Delay Time VDD = 250V, ID = 15A - 400 90 n <t< td=""><td>Inee</td><td>Zero G</td><td>ate Voltage Drain Curre</td><td>ent</td><td></td><td></td><td>-</td><td>-</td><td></td><td>μA</td></t<>	Inee	Zero G	ate Voltage Drain Curre	ent			-	-		μA
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	I _{GSS}	Gate to	Body Leakage Current	t	$V_{GS} = \pm 30V, V_{DS} = 0$	V	-	-	±100	nA
	On Chara	cteristic	S							
		-			Voo = Voo 1 250	A	3.0	-	50	V
g_{FS} Forward Transconductance $V_{DS} = 40V, I_D = 7.5A$ (Note 4) - 23 - 13 Dynamic Characteristics $V_{DS} = 25V, V_{GS} = 0V$ - 1495 1945 p C_{68S} Output Capacitance $V_{DS} = 25V, V_{GS} = 0V$ - 235 310 p C_{68S} Output Capacitance $V_{DS} = 400V, I_D = 15A$ - 20 30 p $Q_{g0}(0)$ Total Gate Charge at 10V $V_{DS} = 400V, I_D = 15A$ - 32 45 n Q_{gd} Gate to Drain "Miller" Charge $V_{DS} = 400V, I_D = 15A$ - 8.5 - n Q_{gd} Gate to Drain "Miller" Charge $V_{DS} = 250V, I_D = 15A$ - 40 90 n $t_d(off)$ Turn-Off Belay Time $V_{DD} = 250V, I_D = 15A$ - 40 90 n $t_d(off)$ Turn-Off Fall Time $V_{DD} = 250V, I_D = 15A$ - 65 140 n $I_d(M)$ Maximum Continuous Drain to Source Diode Forward Current - - <th< td=""><td></td><td></td><td>-</td><td>istance</td><td></td><td></td><td></td><td>0.37</td><td></td><td>ν Ω</td></th<>			-	istance				0.37		ν Ω
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Switching Characteristics Switching Characteristics $t_{d(on)}$ Turn-On Delay Time V_{DD} = 250V, I_D = 15A - 40 90 n $t_{d(off)}$ Turn-On Rise Time V_{DD} = 250V, I_D = 15A - 150 310 n $t_{d(off)}$ Turn-Off Delay Time R_G = 25Ω . - 655 140 n Drain-Source Diode Characteristics Is Maximum Continuous Drain to Source Diode Forward Current - - 15 /////w Is Maximum Pulsed Drain to Source Diode Forward Current - - 1.6 ///w VsD Drain to Source Diode Forward Voltage V_{GS} = 0V, I_{SD} = 15A - - 1.6 //w t_{rr} Reverse Recovery Time V_{GS} = 0V, I_{SD} = 15A - 0.1 - μ Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature 2. 2. 5.5mH, I_{AS} = 15A, V_{DD} = 50V, R_G = 250, Starting T_J = 25°C 3. I_{SD} ≤ 16A, dtd ≤ 2004/µs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C 3. I_{SD} ≤ 16A, dtd ≤ 2004/µs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C 4.		Gate to	to Drain "Miller" Charge					14	-	nC
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trr Reverse Recovery Time $V_{GS} = 0V$, $I_{SD} = 15A$ - 65 - n Qrr Reverse Recovery Charge $dI_F/dt = 100A/\mu s$ (Note 4) - 0.1 - μ Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature 2. L = 5.5mH, $I_{AS} = 15A$, $V_{DD} = 50V$, $R_G = 25\Omega$, Starting $T_J = 25^{\circ}C$ 3. $I_{SD} \le 16A$, $di/dt \le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$ 4. Pulse Test: Pulse width $\le 300\mu s$, Duty Cycle $\le 2\%$ - - - n							-	-		V
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Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature 2. L = 5.5mH, I_{AS} = 15A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. $I_{SD} \le 16A$, di/dt $\le 200A/\mu$ s, $V_{DD} \le BV_{DSS}$, Starting T_J = 25°C 4. Pulse Test: Pulse width $\le 300\mu$ s, Duty Cycle $\le 2\%$,			(Note 4)	-		-	μC
	2. L = 5.5mH, I _{AS} 3. I _{SD} ≤ 16A, di/dt 4. Pulse Test: Pul	= 15A, V _{DD} = ≤ 200A/μs, V se width ≤ 30	= 50V, $R_G = 25\Omega$, Starting $T_J = 2$ $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$ 0µs, Duty Cycle $\le 2\%$	25°C						

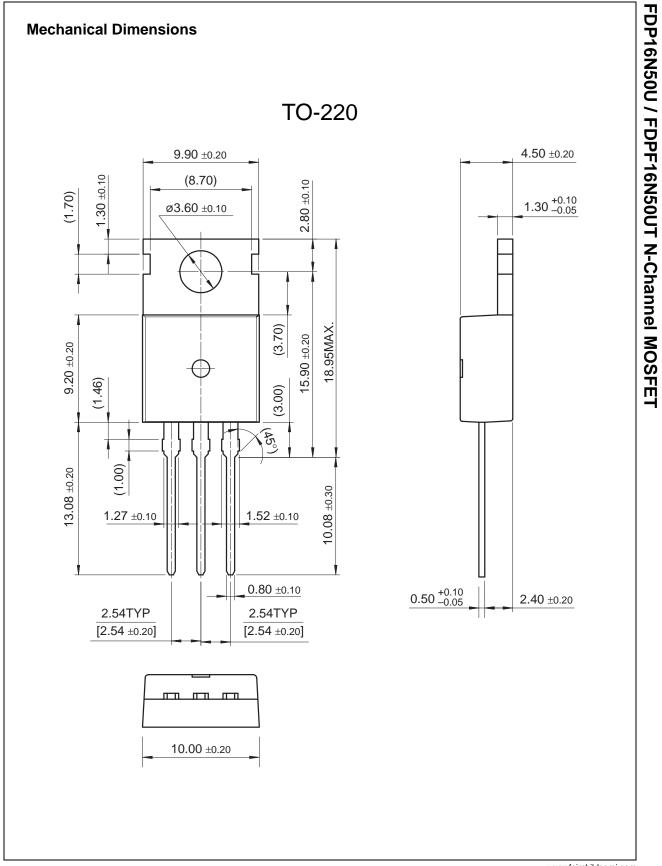




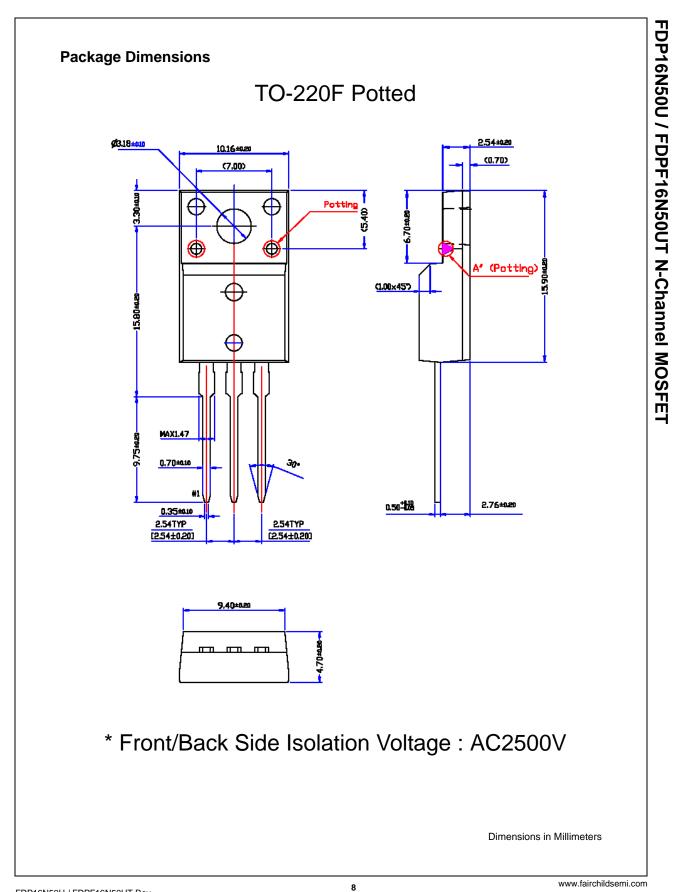


FDP16N50U / FDPF16N50UT N-Channel MOSFET





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SEMICONDUCTOR

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astvCore™	(1)	Sync-Lock™	VisualMax™
ETBench™		SYSTEM ®*	XS™
lashWriter [®] *	PDP SPM™	GENERAL	
	Power-SPM [™]	GENERAL	

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